# Aberration correction in electron microscopy and spectroscopy

Mt. Adams

Mt. Rainier

Ondrej L. Krivanek, microscope builders at Nion Co., and Nion microscope users the world over image taken from an airplane departing from Seattle airport, July 2021

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#### Why is aberration correction important?

Hubble space telescope, before repair. Image is blurred by spherical aberration (**C**<sub>s</sub>) of incorrectly made primary mirror.



After repair: spherical aberration of telescope's mirror is corrected by newly designed planetary camera optics.

Resolution became better, much fainter objects became visible.

In electron microcopy, spherical aberration was just as limiting as it was for the Hubble.

# (S)TEM aberration correction: 50 years from first concepts to successful finish

- **1936:** Scherzer's Theorem: round electron lenses have unavoidable spherical and chromatic aberration.
- **1947:** Scherzer describes several approaches to aberration correction. The most promising: break cylindrical symmetry use non-round optics to correct aberrations.
- **1953-1985:** several proof-of principle correctors are built, but none of them reaches better spatial resolution than the uncorrected instrument.
- **1997** Haider, Rose et al. improve the resolution of a conventional TEM by  $C_s$  correction, in Heildeberg in Germany.
- **1997** Brown, Dellby, Krivanek et al. improve the resolution of a scanning transmission electron microscope (STEM) by  $C_s$  correction, in Cambridge UK.
- **2001-2003 Krivanek and Dellby mark II corrector** reaches direct resolution <1 Å better than any other microscope in the world at that time. Aberration correction takes off.

2020 Electron microscope aberration correction honored by the Kavli Prize in Nanoscience

# (S)TEM aberration correction: 50 years from first concepts to successful finish



Max Haider Knut Urban Harald Rose Ondrej Krivanek

#### Kavli NanoScience Prize winners, 2020

"For sub-ångström resolution imaging and chemical analysis using electron beams."

...the Laureates constructed aberration corrected lenses and made sub-angström imaging and chemical analysis in three dimensions a standard characterization method.

#### 600 kV non-corrected electron microscope



High resolution electron microscope (HREM) built in Cambridge UK ca 1980.

Weight ~ 10 tons, a building wing was needed to house it. Resolution ~ 2Å at 600 kV.

HREM at this resolution unlocked many "atomic secrets".



Au surface reconstruction (Marks and Smith)

# 100 kV $C_s$ -corrected STEM





Aberration-corrected VG STEM built at Nion, 2000.

Weight ~ 1 ton, operated in a converted garage.

Resolution ~1Å at 100 kV. 0.78 Å at 300 kV.

The corrector and the microscope have since been improved substantially.

Updated versions reach 0.5 Å resolution at 200 kV.

Image of instrument at Nion

Instrument schematic

## Results from Nion-corrected VG STEMs



uncorrected

Corrected VG HB501:

Si (110) HADF image showing spacings down to 0.76 Å in a diffractogram.

P.E. Batson et al., Nature 418 (2002) 617.





Corrected VG HB603:

Resolving 0.78 Å dumbbells in (210) Si.

P.D. Nellist et al., Science **305** (2004) 1741.



First direct imaging of sub-Å structures in any type of electron microscope.



#### Progress in single atom imaging by ADF STEM



Chicago STEM ~1975 40 keV: 2.5 Å Au atom Nion UltraSTEM 2007 100 keV: 1 Å Au atom Nion UltraSTEM 2013 200 keV: two Y atomic columns 0.57 Å apart in YAIO<sub>3</sub>

The resolution has improved, and so has the stability.



## BN monolayer with impurities imaged by MAADF

Result of DFT calculation overlaid on an experimental image



MAADF (medium -angle annular DF) image, 60 kV, courtesy Matt Chisholm, ORNL. B, N, C and O

atoms are readily identifiable by their MAADF intensities.

O.L. Krivanek et. al., Nature (2010) 571-574.

#### BN monolayer with impuritie

Result of DFT calculation overlaid on an experime



#### NATURE INSIGHT AGEING

25 March 2010 | www.nature.com/nature | £10

THE INTERNATIONAL WEEKLY JOURNAL OF SCIENCE

#### **ATOM-BY-ATOM ANALYSIS**

Elements mapped by annular dark field electron microscopy

MEASURING SCIENCE Rethinking a flawed system SIRTUIN ACIVATORS Can they delay ageing? CORONARY ARTERIES Vein hope for bypass grafts NATUREJOBS Spotlight on Indiana



#### Results from CEOS-corrected FEI TEMs



Aberration-corrected TEM image of twin boundary in  $BaTiO_3$ . The local intensity values indicate that only 40 and 70% of the O column sites are occupied.

Jia and Urban, Science **303** (2004) 2001.





Aberration-corrected TEM image of a hole in a single layer of graphene. Inset shows an averaged image with improved resolution. *Girit et al., Science* **323** (2009) 1706.







## Primary analytical signals available in a STEM

In the scanning transmission electron microscope (STEM) an electron probe, with ~10<sup>10</sup> fast e- per second and **smaller than one atom,** is scanned across the sample. Many types of interactions of the fast electrons with the sample can be detected, typically in parallel.

Key primary signals:

- 1) Coherent electron scattering: BF imaging, holography, ptychography
- 2) Incoherent electron scattering (from the atomic nucleus), i.e. Rutherford scattering: HAADF imaging
- **3) Inelastic scattering** by sample's electrons: regular electron energy loss spectroscopy (EELS)
- 4) Inelastic scattering exciting atomic vibrations: ultra-high energy resolution EELS



#### Going further: atomic-resolution chemical mapping



Electron energy loss spectra (**EELS**) of La<sub>0.7</sub>Sr<sub>0.3</sub>MnO<sub>3</sub>/SrTiO<sub>3</sub> multilayer structure. Nion UltraSTEM, 100 keV.



Elemental maps constructed by quantifying EELS spectra at every pixel

Muller et al., Science 319, (2008) 1073



#### Fast multi-pass chemical mapping



128 x 128 spectrum image (SI) of an STO / BTO / LMSO multilayer, acquired as 32 separate SIs of 8 s each, aligned and summed (4.3 min total). Dectris ELA hybrid pixel detector, sample courtesy U.C. Irvine

Time-resolved and multi-pass chemical mapping is now possible.





#### Imaging single Si atom impurities in graphene

Si atoms in graphene can occupy two different sites (UltraSTEM images, 60 kV, ca 2010).



4-fold: Si substitutes for 2 C atoms<br/>Courtesy Wu Zhou, ORNL3-fold: Si substitutes for one C atom<br/>Courtesy Matt Chisholm, ORNL

Can we determine the bonding environment of a single atom?



# Probing the bonding of individual atoms by EELS



Lines: experimental EELS spectra recorded in UltraSTEM100

Solid spectra: simulations.

Ramasse et al., Nano Letts (2013), DOI: 10.1021/ nl304187e

Zhou et al., *Phys. Rev. Lett.* (2012)109: 206803

→ atomic environment of a single atom determined by EELS



#### Progress in EM spatial resolution



Denis Gabor (The Electron Microscope, 1948): "Resolution [quest] will have to stop at 0.5 Å, due to lack of objects."

#### Progress in EELS-in-the-EM energy resolution



Figure of merit (FOM) for EELS energy resolution plotted vs. time.

FOM =  $1/(\partial E \lambda)$ 

FOM  $\alpha$  1/(energy resolution x smallest possible illuminated sample area).

It gauges our ability to extract EELS information from very small

(diffraction-limited) sample areas.

The best resolution energy resolution obtained in an electron microscope is now 2.7 meV at 30 kV

Dellby et al., unpublished (2021)

The quest for better energy resolution has not come up against any insurmountable obstacles yet, and further progress is very likely.

#### Recent progress in STEM-EELS energy resolution



All spectra plotted on the same horizontal scale.

Note also the differences in the extent of the ZLP "tail".

#### EELS energy resolution in the EM has improved ~16x in one decade.

## Nion ultra-high resolution monochromator





## Nion U-HERMES<sup>™</sup>\* STEM and Iris EELS



#### Comparison with non-monochromated EELS





#### First glimpses of phonons in the STEM (2014)



# Two types of phonon (vibrational) scattering

#### A) Dipole scattering:

the fast electron interacts with the whole charge distribution in a *polar material*.

The scattering angle is small, and the interaction distance is large.

It is similar to the way infrared photons interact with matter.

Dipole scattering can be selected by placing a small beam away from the sample (aloof spectroscopy) and emphasized by selecting small angles with an aperture.



#### **B) Impact scattering:**

the fast electron passes close to an individual atomic nucleus, transfers a small amount of energy to it, and is scattered by a large angle.

It is similar to the way neutrons scatter from matter.

Impact scattering can be selected by an aperture placed at finite angles in the diffraction plane, and emphasized by placing a small beam close to an atomic nucleus.



# Using dipole scattering to analyze hydrogen bonding

Guanine crystals from Koi fish scales, examined by aloof beam spectroscopy



With the beam 30 nm outside the sample, there is essentially no radiation damage.

Sample courtesy Dwir Gur, Sharon Wolf & Hagai Cohen (Weizmann Institute, Israel)



# Anhydrous guanine: aloof EELS-FTIR comparison

EEL spectrum recorded in "aloof" mode, with ~ 2 nm Ø probe ~30 nm in vacuum (to minimize radiation damage), compared to a Fourier Transform IR (FTIR) spectrum.

Peak	Energy (meV)	Frequency (cm <sup>-1</sup> )	Assignment
а	209	1666	C=O stretch
b	334	2663	C-H stretch
С	357	2846	N-H stretch
d	386	3078	Symmetric NH <sub>2</sub>
е	411	3277	Antisymmetric NH <sub>2</sub>





Peter Rez et al., Nature Coms (2016) DOI: 10.1038/ncomms10945

Biological samples can be analyzed in a damage-free way.



#### Detecting isotopic substitution in L-alanine



Isotopic substitution can be used to study metabolic pathways in cells and whole organisms.



# Momentum-Energy-Temperature exploration in the EM



Temperature dependence of phonon interactions in a nanoscale sample revealed.

# Detecting vibrational changes at a single stacking fault

Optical phonon do not change at a stacking fault in cubic SiC. But acoustic phonons do change!

 $\rightarrow$  Step 1: select q>>0, show the changes at stacking fault

3 mrad max 130 130 3C-SiC 120 120 ₽ 110 110 0 T0,L0 8 100 100 Loss (meV) Energy Loss (meV) то 90 Energy (meV) 8 80 \_A 4 2 70 8 60 Energy 3 ¥ TΑ \$ 30 8 8 20 distance from stacking fault (nm) 10 2 mrad 0.08 0.04 0.00 min w Intensity (a.u.) X. Yan et al., Nature 589 (2021) 65-69

Phonon changes at individual defects detected.

→ Step 2: map the signal in real space

stacking

fault

#### Phonons due to a *single Si atom* in graphene



Phonon spectrum of a single Si atom has been recorded.

## Summary

- Aberration-corrected (S)TEM and ultra-high energy resolution EELS have progressed remarkably since the 1990s.
- There have been major developments in both instrumentation and in theory.
- Many new capabilities are now available, leading to major new results.



#### Conclusion: new instruments do open up new worlds!



Galileo Galilei and two of his telescopes



Niklas Dellby (Nion co-founder), Christian Colliex, Odile Stephan, Katia March, Marcel Tence and the first complete aberration-corrected EM Nion built, for CNRS Orsay

Galileo's telescope changed our view of the world. Aberration-corrected electron microscopes and spectrometers are changing our view of the nanoworld.

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